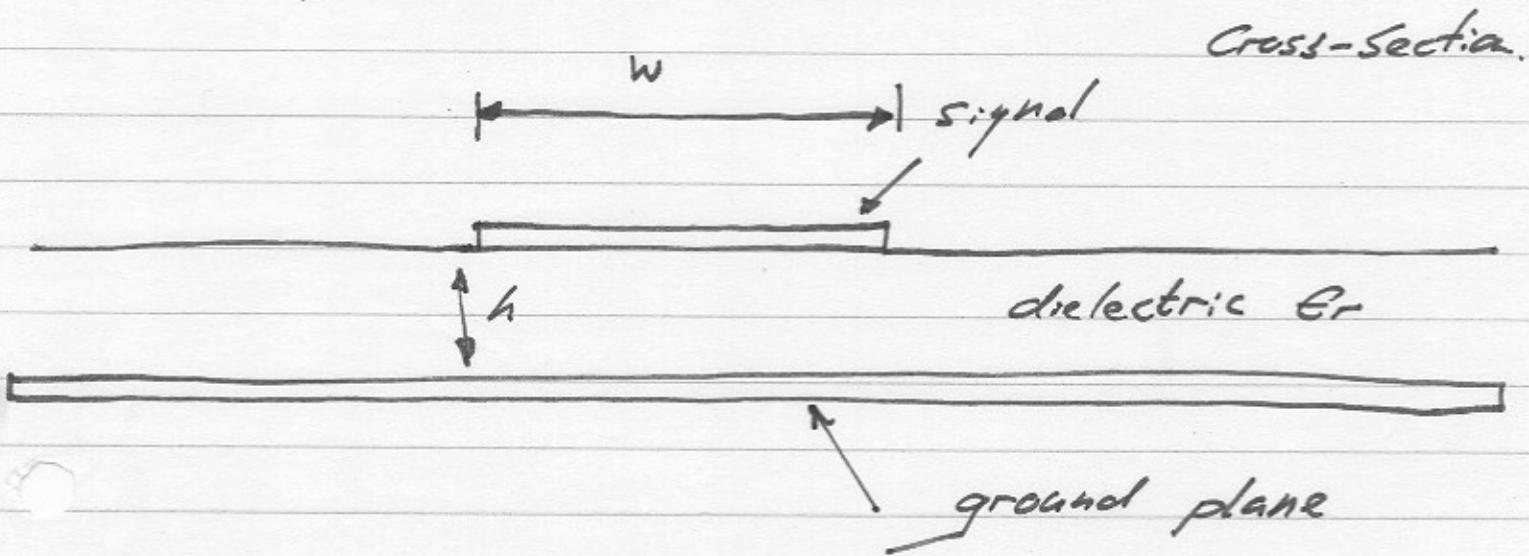


ECE 202A Notes set 3

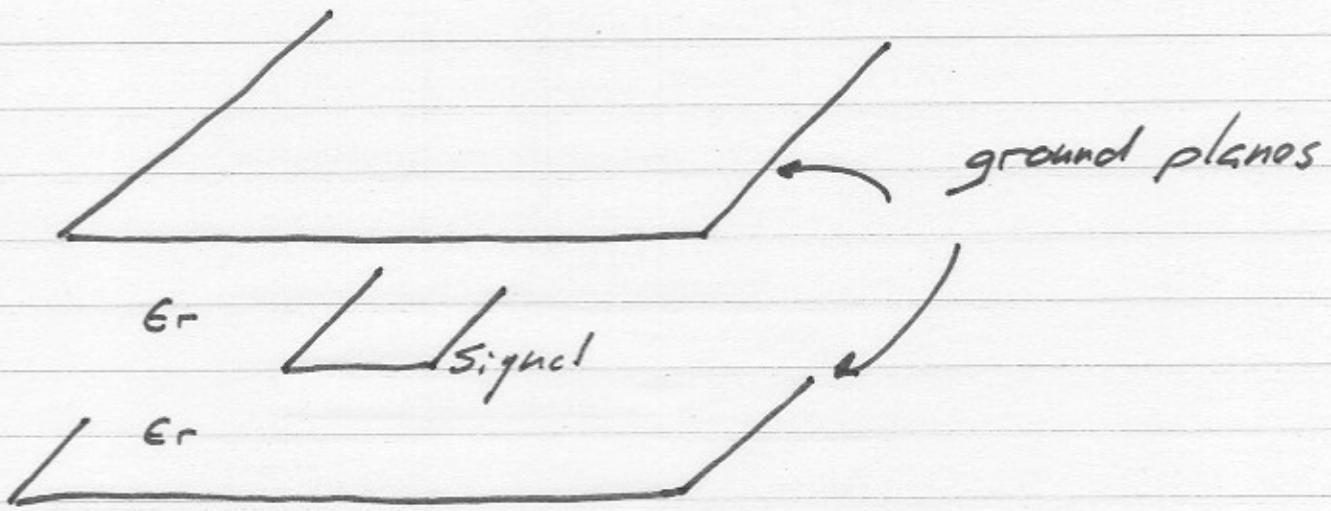
Planar transmission lines

Microstrip transmission line:



Some expressions for Z_0 & v given in text. The CAD program LINECALC is more useful. We will also develop here some approximate expressions.

Compare microstrip to stripline



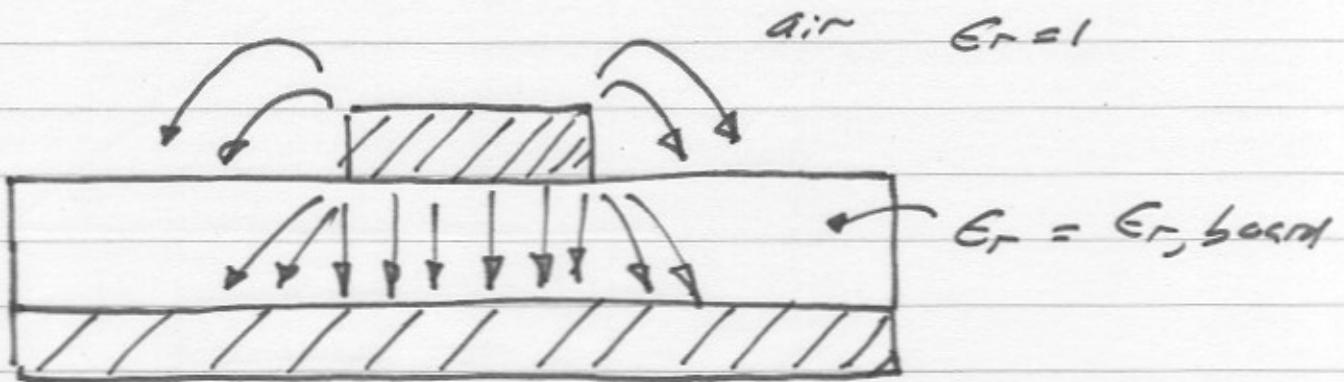
This is made by sandwiching 2 pc boards together.

All fields are within material of ϵ_r .

Hence velocity = $c / \sqrt{\epsilon_r}$

(3)

In microstrips, the fields are partly in air



so for wide lines, the fields are almost all in board, while narrower lines will have proportionally more field energy in air.

$$\text{Wide lines: } v \approx \frac{c}{\sqrt{\epsilon_r}}$$

(4)

For lines of non-infinite width (w/H)
 $v \neq c/\sqrt{\epsilon_r}$. This leads to the idea of
 an effective dielectric constant

$$\epsilon_{r,\text{eff}} \triangleq \frac{c^2}{v^2}$$

so that $v = c/\sqrt{\epsilon_{r,\text{eff}}}$

The text gives, for example, that

$$\epsilon_{r,\text{eff}} \approx \frac{\epsilon_r + 1}{2} - \frac{\epsilon_r - 1}{2} \left(1 + 12 \frac{h}{w}\right)^{-1/2}$$

very roughly.

Advice: Ignore above formula, and use
LINECALC.

(5)

Characteristic Impedance:

For wide lines ($w/h \gg 1$), there is a uniform plane wave between the conductors and negligible fringing field.

$$\Rightarrow Z_0 = \sqrt{\frac{\mu_0}{\epsilon_0}} \sqrt{\frac{1}{\epsilon_r}} \cdot \frac{h}{w} \text{ as } W/H \rightarrow \infty$$

this is not applicable to lines of reasonable width.

Generally Z_0 & v are determined by electromagnetic calculations. Results are effectively tabulated in common CAD programs.

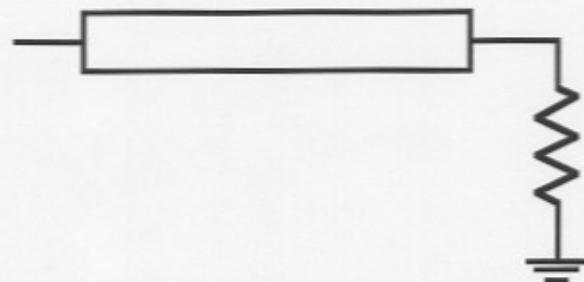
Some typical material parameters

Line parameters are for W=W

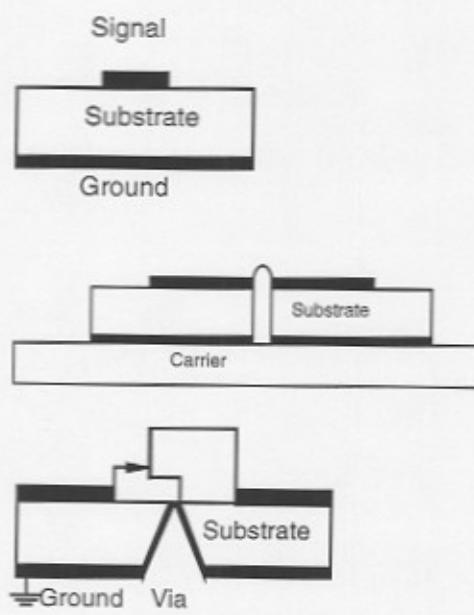
Dielectric	ϵ_r	$\epsilon_{r,eff}$	vphase	Z_0
Duriod	2.2	1.77	3/4 c	85Ω
epoxy-glass	4.8	3.28	0.55 c	66Ω
Alumina (Al ₂ O ₃)	9.8	4.18	0.5 c	40Ω
GaAs	13	5.3	0.43 c	35 Ω
Quartz (SiO ₂)	3.8			

duriod is available in a variety of dielectric constants. Sapphire (crystalline Al₂O₃) is sometimes used, but is anisotropic. SiO₂ is used both in its crystalline form (Quartz) and in amorphous form (fused silica)

Vias in microstrip:



We need a home in the board. This is fairly easy in 202a (drill a hole and pass a wire through it) but some wiring inductance will result. This will be a key problem in circuit construction. Vias are a very serious difficulty for microwave ICs both because of fabrication difficulties (etch a hole through the substrate, electroplate it) and because of the ≈ 12 pH inductance. The higher the frequency, the more of a problem this inductance will become.



Microstrip Line

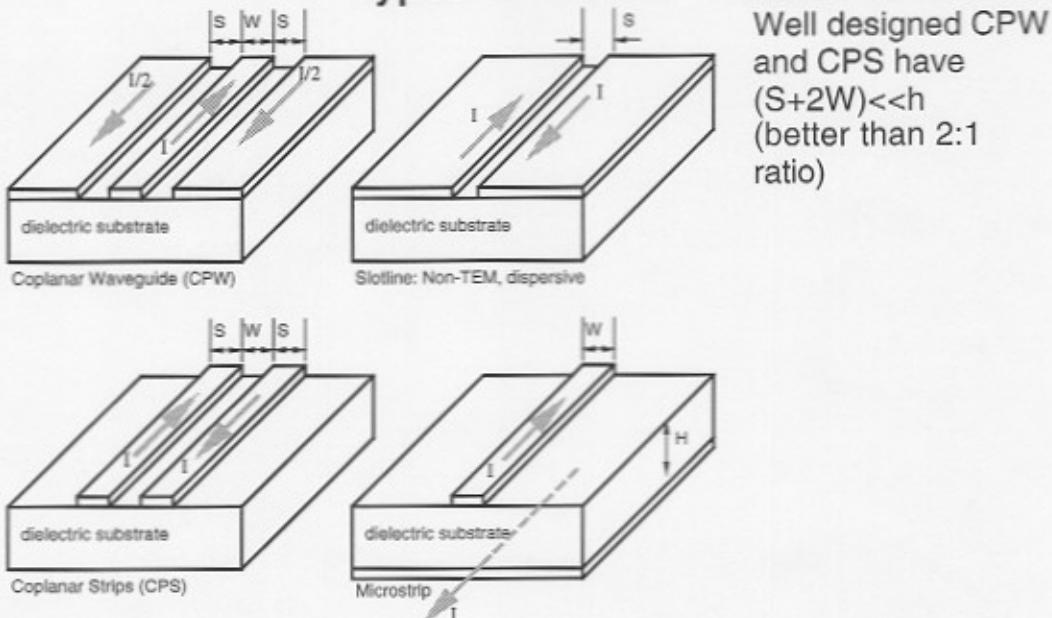
Dominant transmission medium in microwave IC's

Key advantage: IC interconnections have very low ground lead inductance- more important than signal line inductive parasitics in amplifiers

Key problem: through-wafer grounding holes (vias).
Via inductance forces progressively thinner wafers at higher frequencies. Microstrip is used with good performance in 65 GHz monolithic circuits

Coplanar Lines, Coplanar Strip

Types of Planar Transmission Lines



For these structures, if $H \gg S+2W$

$$\epsilon_{r,eff} = \frac{\epsilon_r + 1}{2}$$

Advantages:

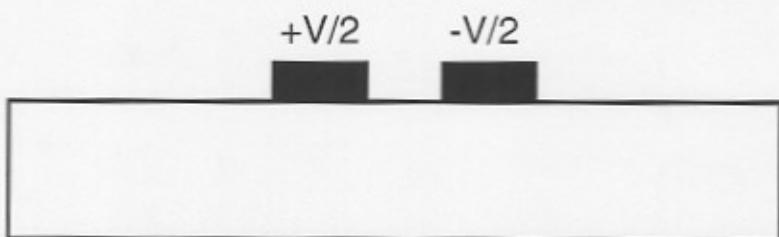
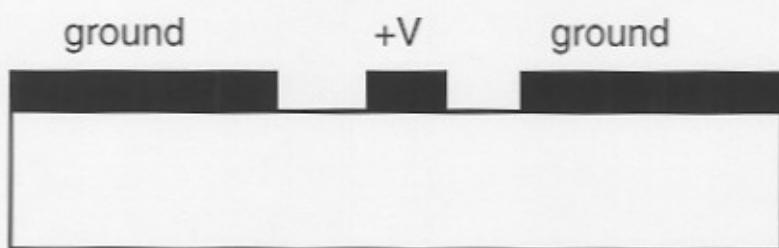
Don't need backside ground plane, don't need to etch vias, easy ground connection without inductance

disadvantages:

need to tie the two ground planes together periodically, difficulty in maintaining the ground-plane connection on one IC the same as on the IC or package to which it is connected (more on this later)

(9)

Coplanar Waveguide is a unbalanced transmission line,
while coplanar strips is balanced:



If the substrate is thick and the metal thin
Z₀ depends only on the ratio s/w

Parasitic modes on transmission lines:

2 classes of modes:

Quasi-TEM: circuit-like, require 2 wires

Non-TEM: modes similar to waveguide, optical fiber, etc.

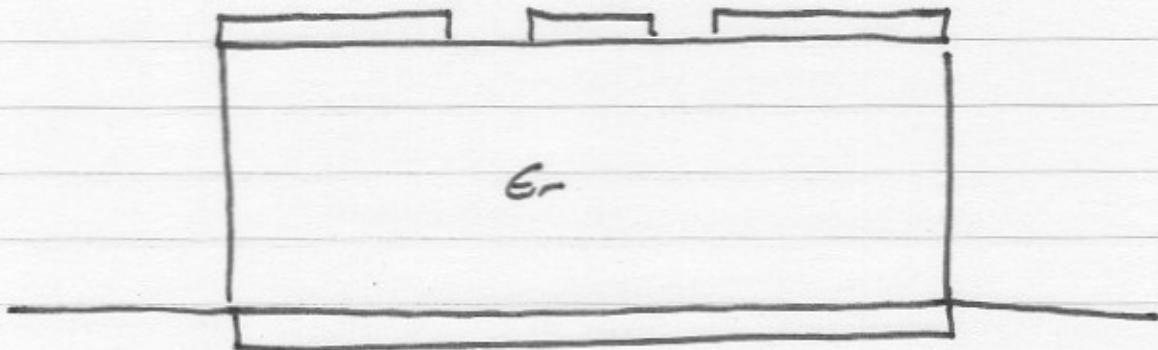
Let's consider circuit-like modes first.

A system with N conductors will propagate $(N-1)$ quasi-TEM modes.

Let's consider an example:

(11)

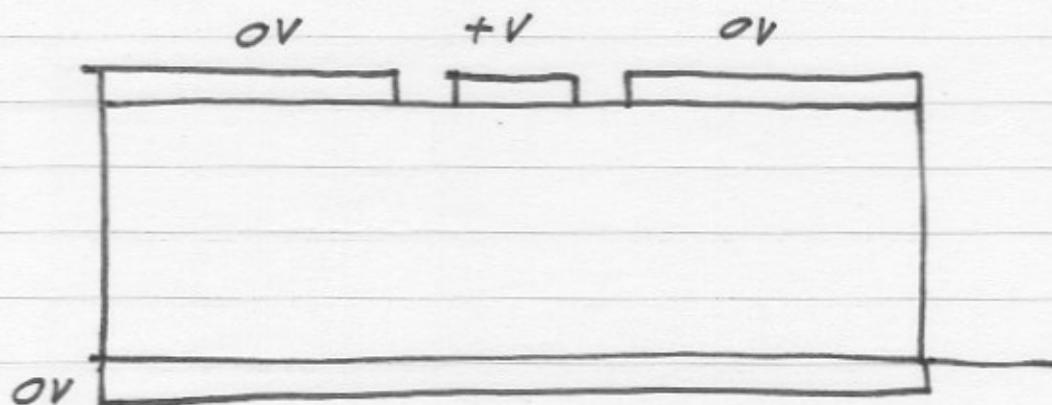
Parasitic Modes on Coplanar Waveguide



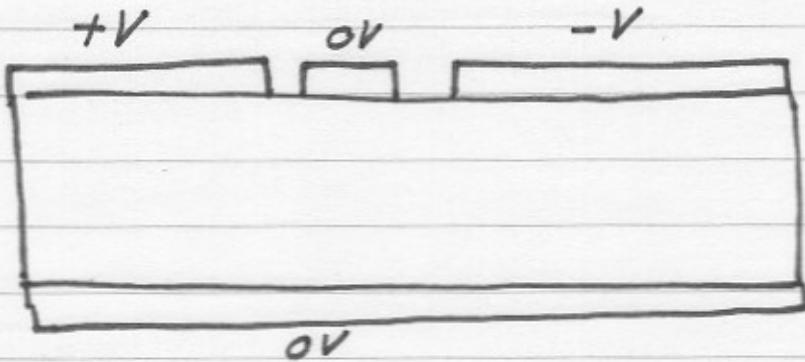
Ground (brass carrier)

There are 4 conductors, hence 3 modes!

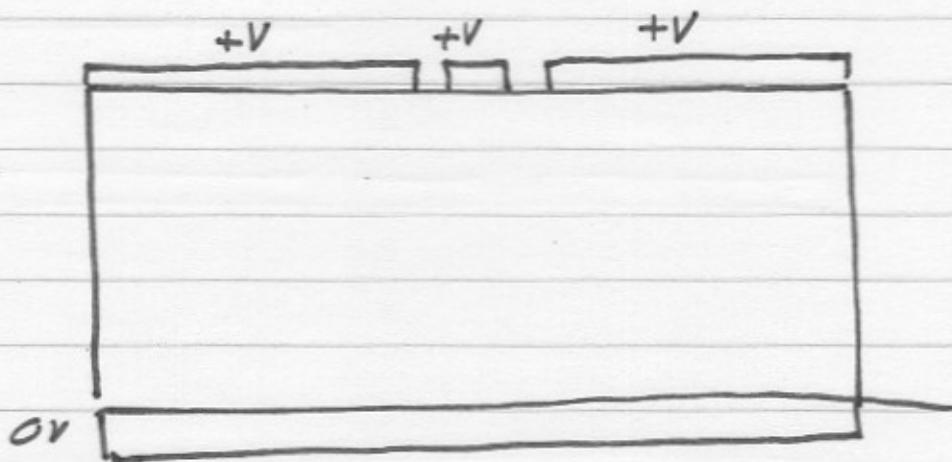
CPW mode (desired)



(waves propagate in both directions)

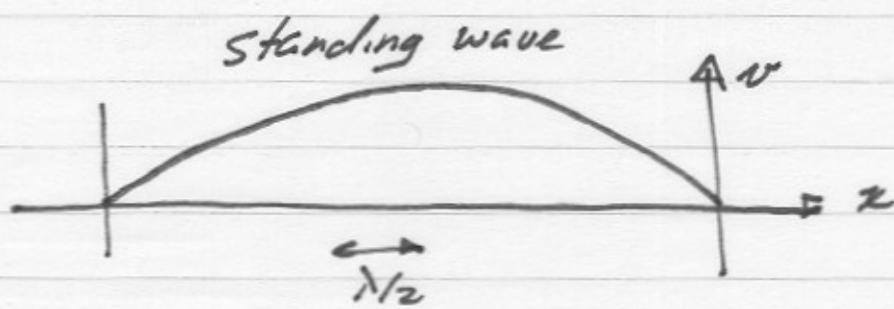
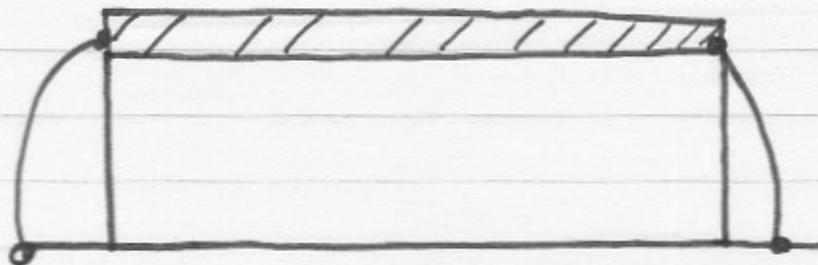
CPS mode:

This is suppressed by connecting the 2 grounds together at distances $< \lambda/8$.

Microsrip mode

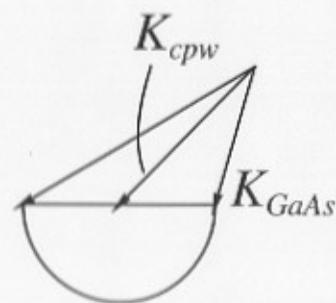
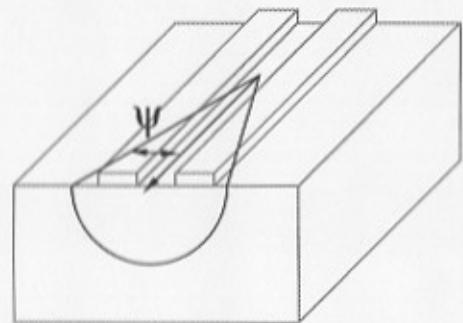
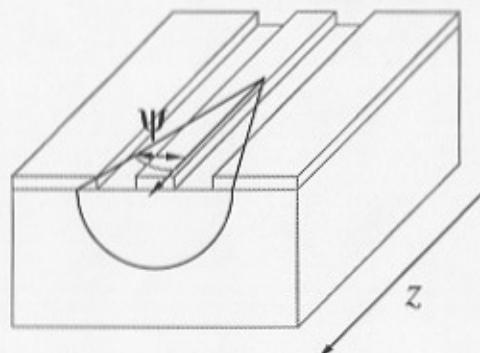
This is [possibly] suppressed by connecting the CPW ground planes to the gross carrier.

The problem is that if the chip is $>\lambda/2$ wide we will not suppress these modes by grounding at the chip boundary:



This is the problem with coplanar waveguide: maintaining the same ground potential on chips connecting together.

Transmission-Line Radiation Losses



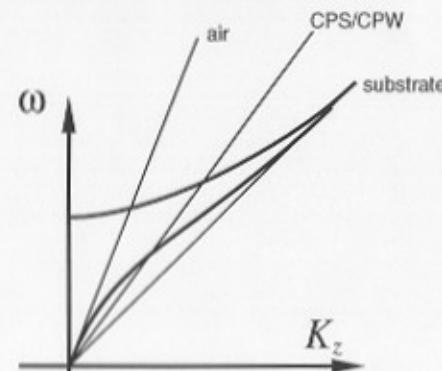
Transmission line velocity is

$$v = c / \sqrt{(1 + \epsilon_r) / 2}$$

Velocity of a plane wave in the substrate is $v = c / \sqrt{\epsilon_r}$, which is slower.

Power radiates at angle ψ determined by matching K_z .

With substrate of finite thickness, radiation shows frequency structure due to substrate modes



Radiation generally refers to the other class of problems: coupling energy into non-TOM modes propagating in the substrate.

Radiation loss is radiation into substrate modes

To radiate we must

- be able to match wavelength in direction of propagation (k_z matching)
- have significant field overlap.
- Substrate modes must exist.

k_z matching is possible because of the wave speed

Several comments regarding radiation:

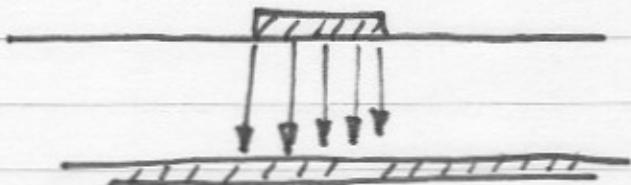
1) Radiation not important when substrate
is thin compared to λ_d .

In this case the modes are either
forbidden or have velocities approaching c
(hence K_y can't match)

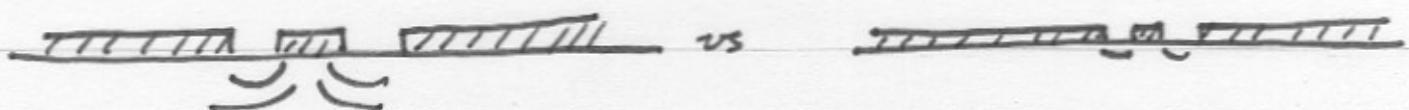
2) Radiation can be eliminated by slowing.

Lines can be designed with a slow wave velocity.
Radiation then not possible. But slow-wave
lines have other problems.

3) Coupling depends on geometry.



Microstrip has fields throughout the substrate
and couples strongly with many modes.



Coplanar waveguide (and coplanar strip)

can be scaled to fine dimensions which result
in small field penetration into the substrate and
therefore small radiation.

For CPS/CPW:

$$d_{rad} \propto (S + 2W)^2 \cdot f^3$$

For Microstrip lines, radiation problems will demand that the substrate become thinner as the operating frequency increases.

For Integrated circuits, this becomes a problem with breakage.

Dispersion

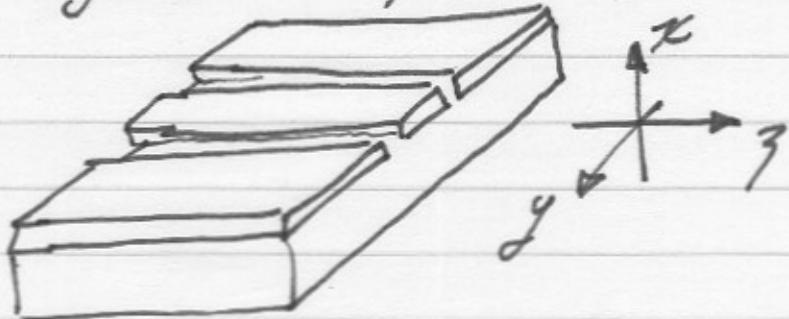
Modes are in a mixed-dielectric medium.

Quasi-TEM mode = sum of spatial harmonics

Each spatial harmonic must satisfy:

$$\text{in air } k_x^2 + k_y^2 + k_{zA}^2 = k_A^2 = \omega^2/c^2$$

$$\text{in board } k_x^2 + k_y^2 + k_{zB}^2 = k_B^2 = \epsilon_r \omega^2/c^2$$

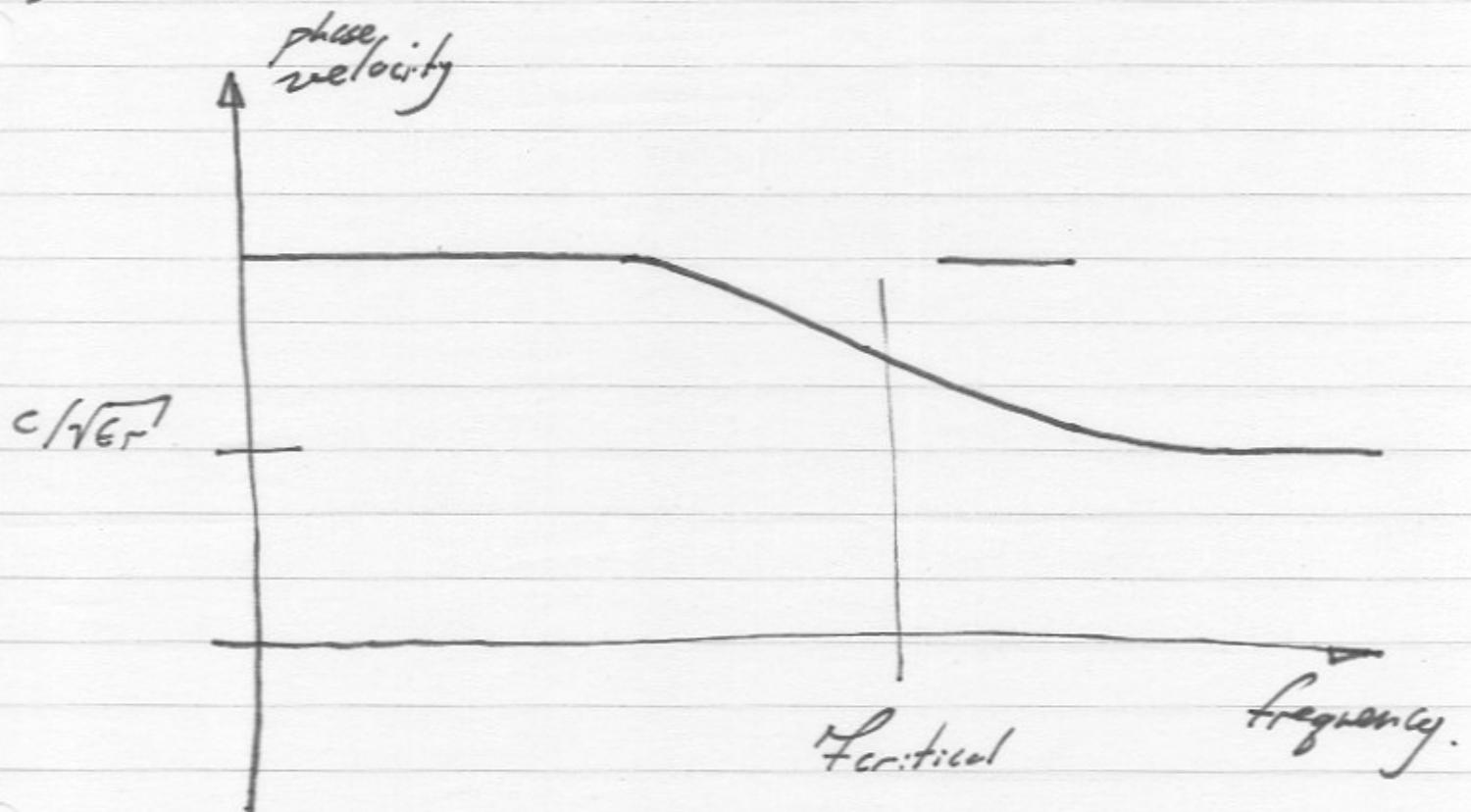


We must also have $k_{zA} = k_{zB} = k_z$ and

$$k_{yA} = k_{yB} = k_y$$

This is a boundary-value problem. Let's not bother solving it, but just observe some general points:

- As frequencies increase, fields will concentrate themselves in the high- ϵ material
- velocity will decrease at higher frequencies.
- Frequency at which strong changes are observed is inversely proportional to the lines' lateral dimensions.



at Critical, transverse d.mens. $\equiv \lambda d$.

Engineering Observation:

Near feritics, change in velocity is large
but

line is also radiating strongly

- So line is of little value anyway.

At frequencies of feritic 1/10, or so,

there will be small changes in velocity.

This will be important for those systems

using transmission lines as high-Q elements.

Skin-effect losses

in metal, waves propagate as

$$E(z) = E_0 e^{-\gamma z}, \quad \gamma = \alpha + j\beta$$

where the propagation constant γ

$$\gamma = \sqrt{j\omega\mu(\omega\sigma + \tau)}$$

τ is the conductivity.

at Microwave Frequencies in metal, $\tau \gg \omega\sigma$

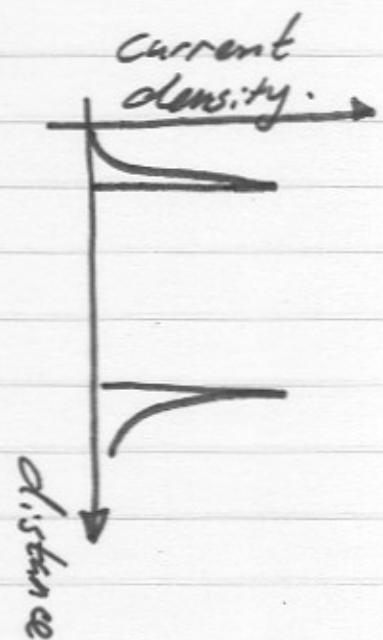
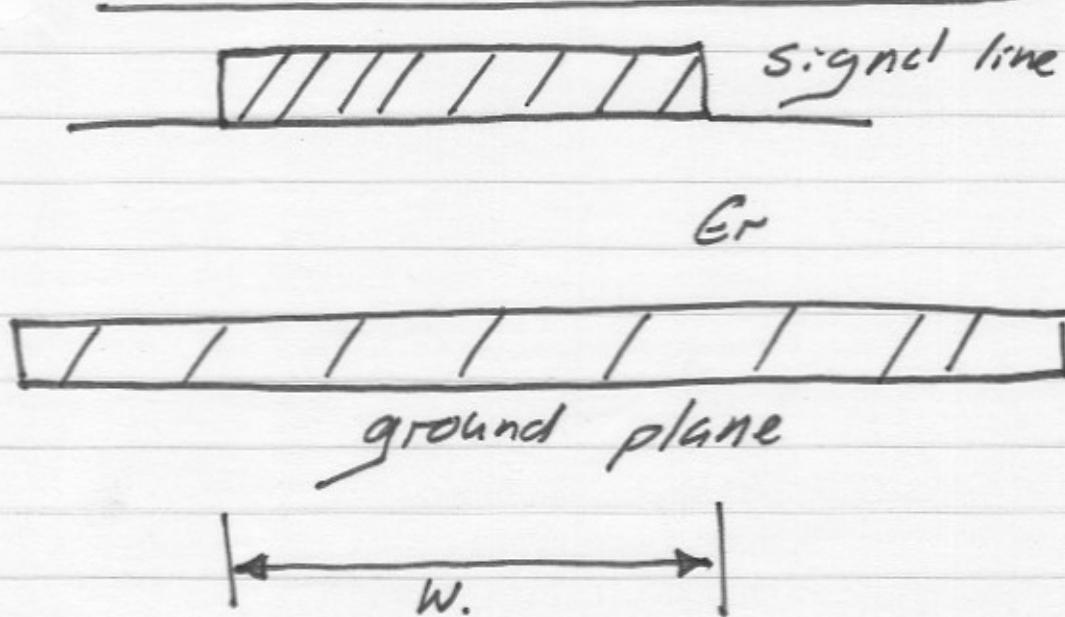
and

$$\gamma = \sqrt{j\omega\mu\tau}$$

→ current penetrates in metal for
a depth of

$$\delta = \frac{1}{\alpha_{\text{metal}}} = \sqrt{\frac{2}{\omega\mu\tau}}$$

for a wide microstrip Line:



... the current has an exponential distribution near the 2 conductor surfaces of "thickness" (exponential decay length) δ .

metal sheet resistance = ρ_{sheet}

$$= \frac{1}{S\sigma} = \sqrt{\frac{\omega\mu'}{2\sigma}}$$

resistance per unit length

$$R = \frac{\rho_{\text{sheet}} \cdot Z}{W} = 2 \cdot \frac{1}{W} \sqrt{\frac{\omega\mu'}{2\sigma}}$$

Signal and ground

This gives rise to attenuation per unit length along the transmission line of

$$\alpha = \frac{\text{series resistance per unit length}}{2Z_0}$$

$$= \frac{1}{2Z_0} \frac{1}{w} \sqrt{\frac{c\mu}{2\sigma}}$$

Note that we have assumed a wide microstrip line - this gives a uniform lateral distribution of current and a ' $1/w$ ' dependence. Narrow Microstrip lines and coplanar lines have an uneven lateral current distribution and the term ' $1/w$ ' is wrong. Loss still varies as $\sqrt{c\mu}$

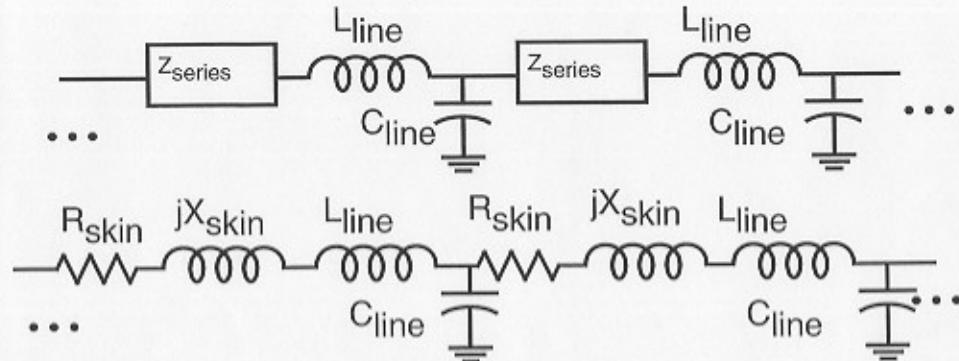
Skin Effect Losses, I

$$\gamma_{metal} = \sqrt{j\omega\mu(j\omega\varepsilon + \sigma)} \\ \equiv \sqrt{j\omega\mu\sigma}$$

$$\alpha_{metal} + j\beta_{metal} = \sqrt{\omega\mu\sigma/2} + j\sqrt{\omega\mu\sigma/2} \\ = (1/\delta)(1+j)$$

where $\delta = \sqrt{2/\omega\mu\sigma}$

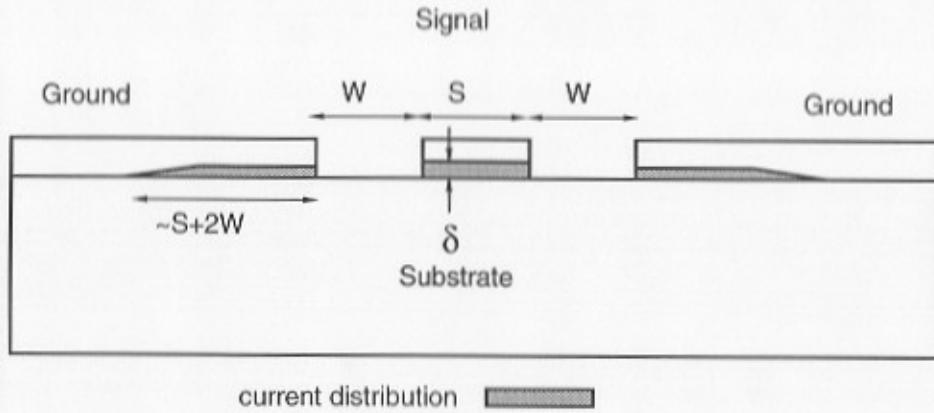
$$Z_{series} = \gamma_{metal}/\sigma P \\ = (1/\delta\sigma P) + j(1/\delta\sigma P)$$



Surface impedance of the metal interconnections of a transmission line introduces loss proportional to the square root of frequency.

Dispersion is also introduced, as the skin impedance has equal real and complex parts

Skin Effect Losses II



For a coplanar line the effective current carrying periphery P is approximately the width of the center conductor (IF S is relatively small compared to W , a higher-impedance line)

$$\begin{aligned}\gamma_{line} &= \sqrt{j\omega C(j\omega L_{line} + Z_{series})} \\&= j\omega\sqrt{LC}\sqrt{1 + (Z_{series}/j\omega L_{line})} \\&\approx j\omega\sqrt{LC}\left(1 + (Z_{series}/2j\omega L_{line})\right) \\&= j\omega\sqrt{LC} + \frac{Z_{series}}{2Z_0} \\Z_0 &= \sqrt{L/C}\end{aligned}$$

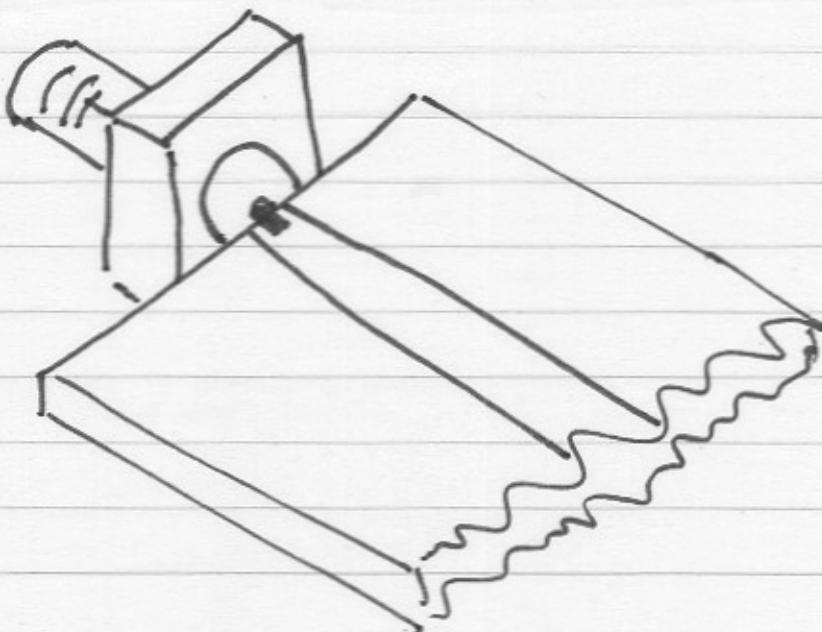
Following this, the line propagation constant γ can be found, and the transfer function for a line of length l is $\exp(-\gamma l)$

$$Z_{series} = (1/\delta\sigma P) + j(1/\delta\sigma P)$$

Discontinuities:

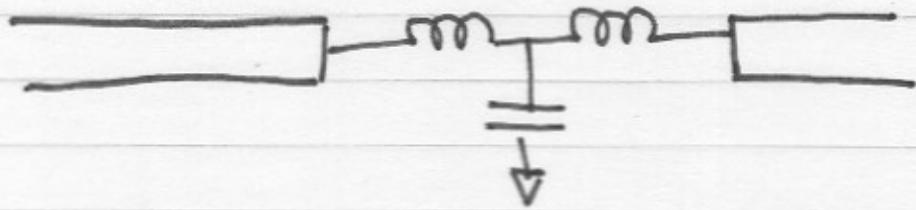
big problem: launching

different field configurations in
coaxial cable and microstrip.



as current distributions and field distributions for the fundamental modes are different on the 2 sides of the junction, higher-order modes H_{11} are excited in order to satisfy the boundary conditions.

- * If these higher-order modes can propagate we lose power \rightarrow disastrous.
- * If the higher-order modes cannot propagate, they are evanescent, not propagating but storing energy within one decay length of the junction.
- * The evanescent mode energy is modelled by reactive junction parasitics, thus:

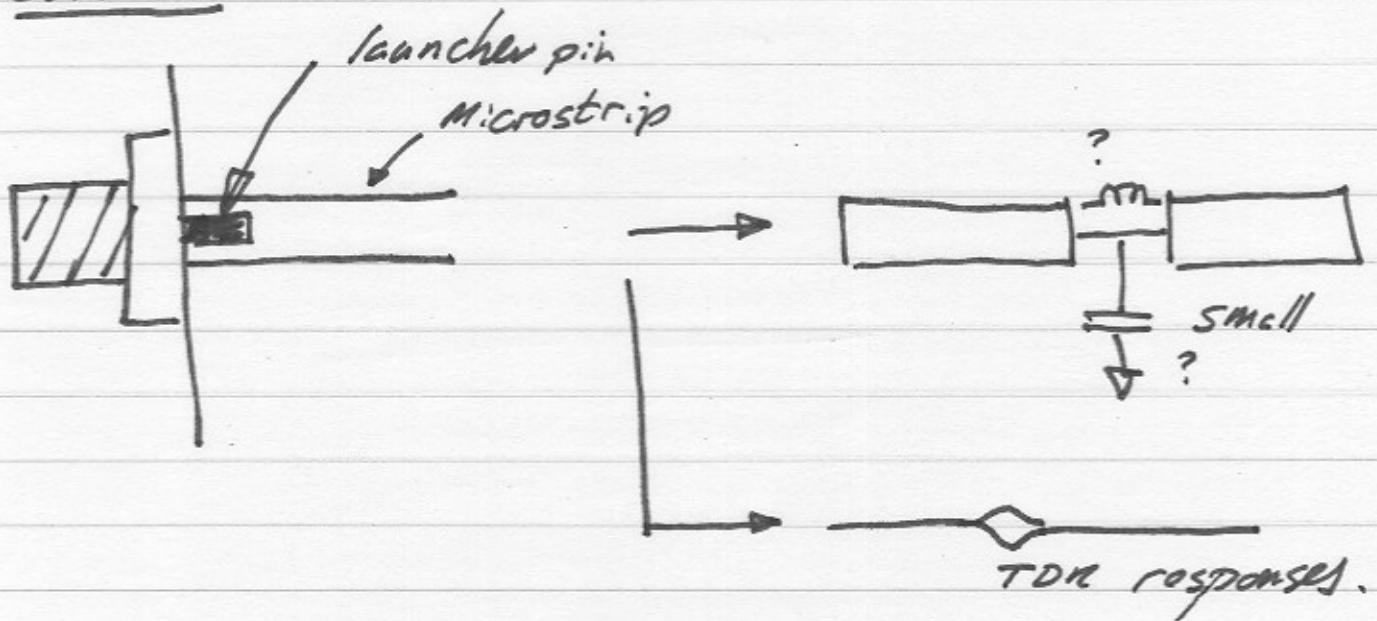


Values are determined by computer simulations;

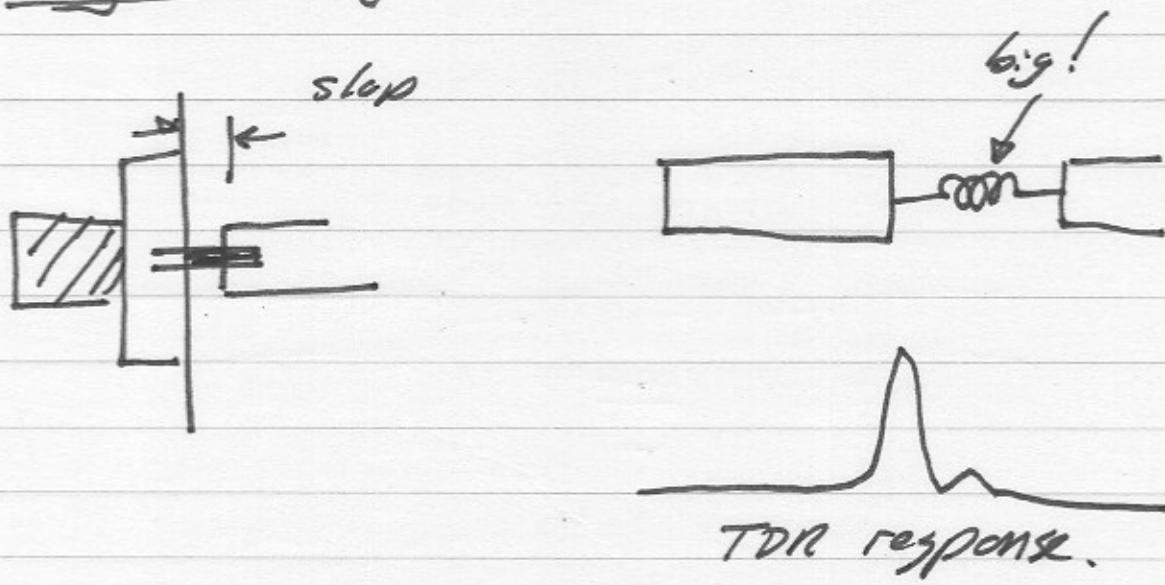
Common microwave CAD programs have junction models.

Make sure your launchers are precisely assembled.

Correct:

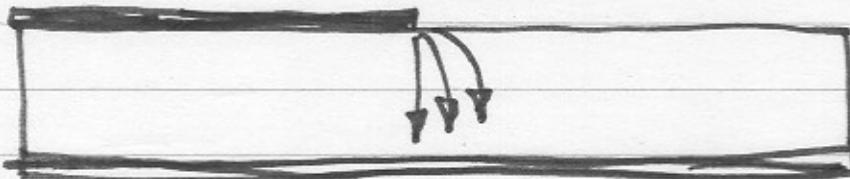


sloppy assembly:



other discontinuities:

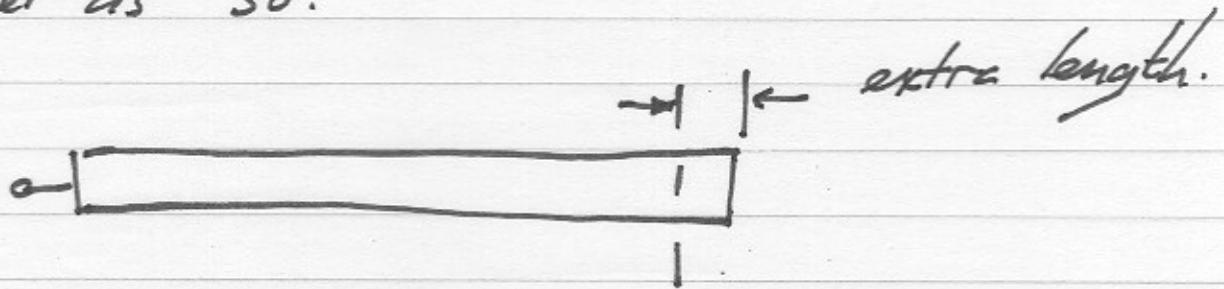
End effect



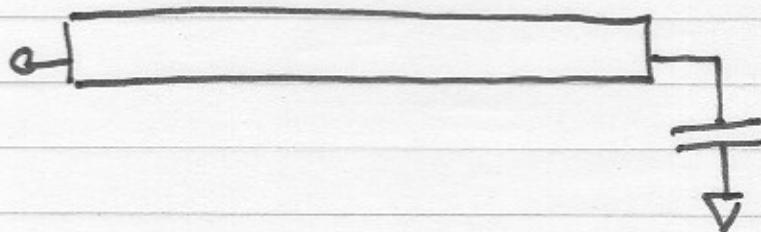
line has Fringing Fields

acts a bit longer:

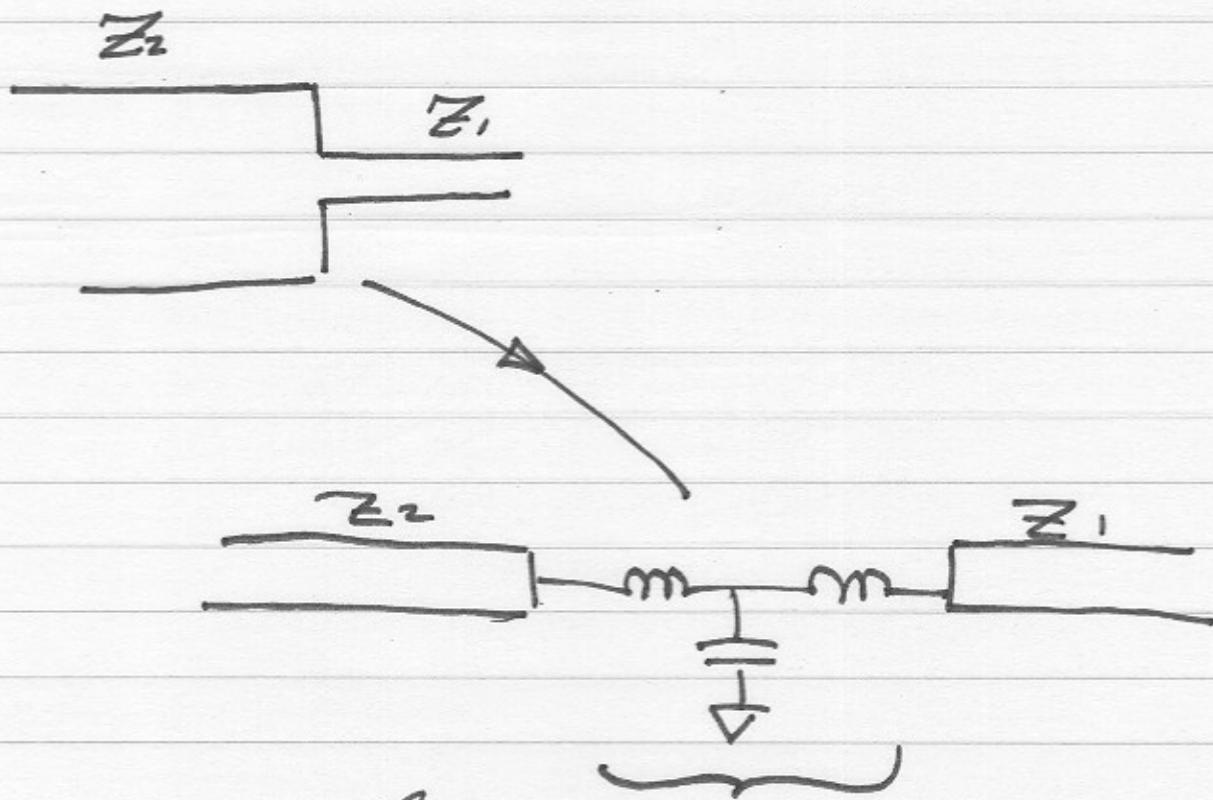
model as so:



or



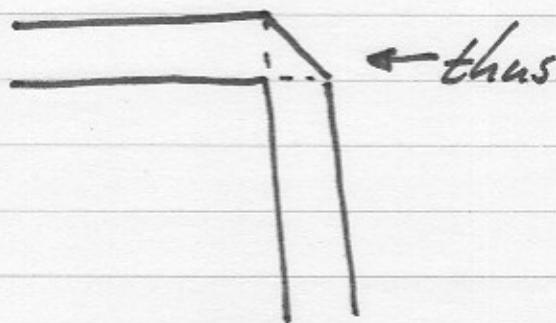
Change in Line Geometry



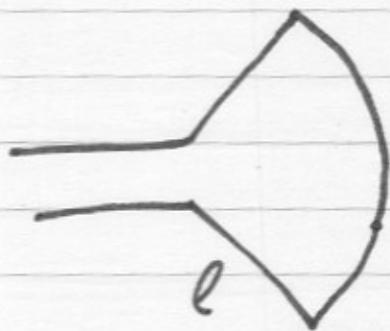
parasitics from junction evanescent modes.

Corners have similar models

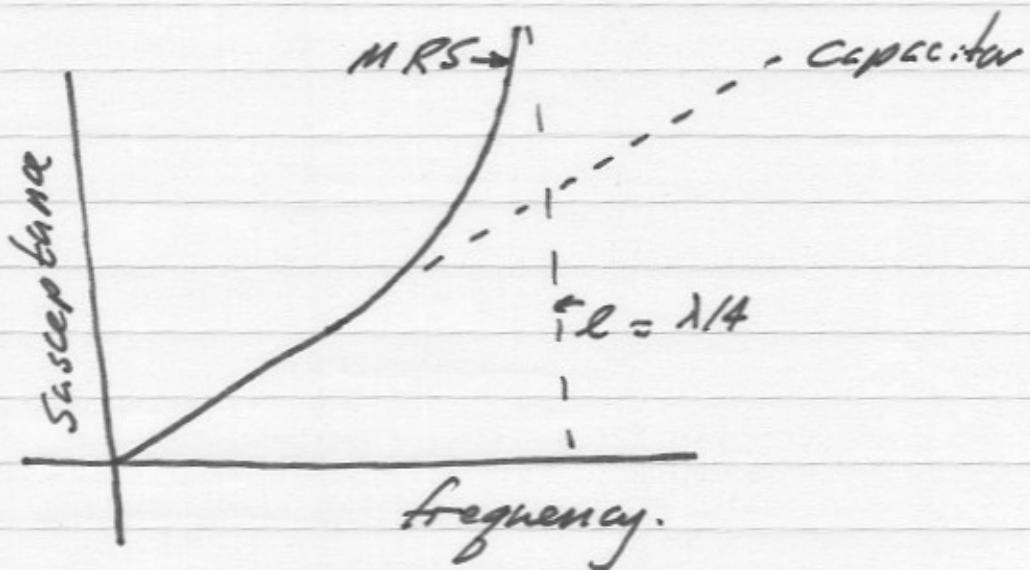
Parasitics are smallest if junctions are mitred:



Microstrip radial stub

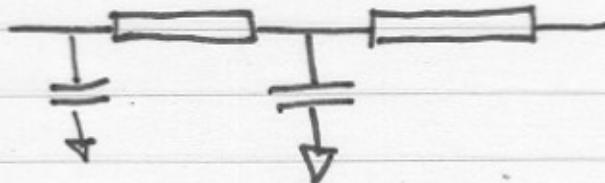


basically an open-circuited
line of impedance varying
with distance:

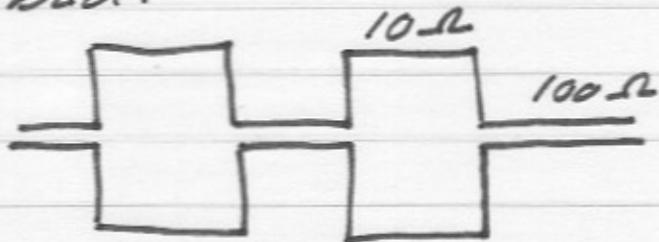


why use it:

matching network:

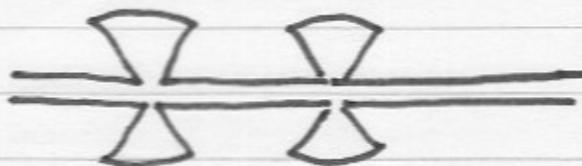


physical realization - bad:



problems with transverse modes on low-Z lines

alternative:



Comment: no useful analytical model for radial stub. Design matching network using a capacitor, find a stub having the same susceptance over the required bandwidth, and substitute.